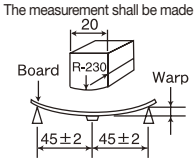
可靠性数据 RELIABILITY DATA

Multilayer Ceramic Capacitor Chips

Item	Specified Value				Test Methods and Remarks
	Temperature Compensating (Class 1)		High Permitivity (Class 2)		
	Standard	High Frequency Type	Standard Note1	High Value	
1.Operating Temperature Range	−55 to +125℃		BJ：−55 to +125℃ F：−25 to +85℃	−25 to +85℃	High Capacitance Type BJ (X7R)：−55~+125℃, BJ (X5R)：−55~+85℃ E (Y5U)：−30~+85℃, F (Y5V)：−30~+85℃
2.Storage Temperature Range	−55 to +125℃		BJ：−55 to +125℃ F：−25 to +85℃	−25 to +85℃	High Capacitance Type BJ (X7R)：−55~+125℃, BJ (X5R)：−55~+85℃ E (Y5U)：−30~+85℃, F (Y5V)：−30~+85℃
3.Rated Voltage	50VDC,25VDC, 16VDC	16VDC 50VDC	50VDC,25VDC	50VDC,35VDC,25VDC 16VDC,10VDC,6.3VDC 4DVC, 2.5VDC	
4.Withstanding Voltage Between terminals	No breakdown or damage	No abnormality	No breakdown or damage		Applied voltage: Rated voltage×3 (Class 1) Rated voltage×2.5 (Class 2) Duration: 1 to 5 sec. Charge/discharge current: 50mA max. (Class 1,2)
5.Insulation Resistance	10000 MΩ min.		500 MΩ μF. or 10000 MΩ., whichever is the smaller. Note 5		Applied voltage: Rated voltage Duration: 60±5 sec. Charge/discharge current: 50mA max.
6.Capacitance (Tolerance)	0.5 to 5 pF: ±0.25 pF 1 to 10pF: ±0.5 pF 5 to 10 pF: ±1 pF 11 pF or over: ± 5% ±10% 105TYPER△, S△, T△, U△ only 0.5~2pF: ±0.1pF 2.2~20pF: ±5%	0.5 to 2 pF : ±0.1 pF 2.2 to 5.1 pF : ±5%	BJ: ±10%, ±20% F：$^{+80}_{-20}$%	BJ：±10%、±20% F：−20%／+80%	Measuring frequency： Class1： 1MHz±10% (C≦1000pF) 1 k Hz±10% (C>1000pF) Class2： 1 k Hz±10% (C≦10 μF) 120Hz±10Hz (C>10 μF) Measuring voltage： Note 4 Class1：0.5~5Vrms (C≦1000pF) 1±0.2Vrms (C>1000pF) Class2： 1±0.2Vrms (C≦10 μF) 0.5±0.1Vrms (C>10 μF) Bias application: None
7.Q or Tangent of Loss Angle (tan δ)	Under 30 pF ：Q≧400 + 20C 30 pF or over ：Q≧1000 C= Nominal capacitance	Refer to detailed specification	BJ: 2.5% max. (50V, 25V) F: 5.0% max. (50V, 25V) Note 4	BJ：2.5% max. F：7% max. Note 4	Multilayer: Measuring frequency： Class1： 1MHz±10% (C≦1000pF) 1 k Hz±10% (C>1000pF) Class2： 1 k Hz±10% (C≦10 μF) 120Hz±10Hz (C>10 μF) Measuring voltage： Note 4 Class1：0.5~5Vrms (C≦1000pF) 1±0.2Vrms (C>1000pF) Class2： 1±0.2Vrms (C≦10 μF) 0.5±0.1Vrms (C>10 μF) Bias application: None High−Frequency−Multilayer: Measuring frequency: 1GHz Measuring equipment: HP4291A Measuring jig: HP16192A
8.Temperature Characteristic of Capacitance (Without voltage application)	CK：0±250 CJ：0±120 CH：0±60 CG：0±30 RH：−220±60 SK：−330±250 SJ：−330±120 SH：−330±60 TK：−470±250 TJ：−470±120 UK：−750±250 UJ：−750±120 SL：+350 to −1000 (ppm/℃)	CH：0±60 RH：−220±60 (ppm/℃)	BJ：±10% (−25~85℃) F：$^{+30}_{-80}$% (−25~85℃) BJ (X7R)：±15% F (Y5V)：$^{+22}_{-82}$%	BJ：±10% (−25~+85℃) F：+30%／−80% (−25~+85℃) BJ (X7R、X5R)： ±15% F (Y5V)： +22%／−82%	According to JIS C 5102 clause 7.12. Temperature compensating: Measurement of capacitance at 20℃ and 85℃ shall be made to calculate temperature characteristic by the following equation. $\frac{(C_{85}-C_{20})}{C_{20}\times\triangle T}\times 10^{6}$ (ppm/℃) High permitivity: Change of maximum capacitance deviation in step 1 to 5 Temperature at step 1: +20℃ Temperature at step 2: minimum operating temperature Temperature at step 3: +20℃ (Reference temperature) Temperature at step 4: maximum operating temperature Temperature at step 5: +20℃ Reference temperature for X7R, X5R, Y5U and Y5V shall be +25℃
9.Resistance to Flexure of Substrate	Appearance: No abnormality Capacitance change: Within ±5% or ±0.5 pF, whichever is larger.	Appearance: No abnormality Capacitance change: Within±0.5 pF	Appearance: No abnormality Capacitance change: BJ：Within ±12.5% F：Within ±30%		Warp: 1mm Testing board: glass epoxy−resin substrate Thickness: 1.6mm (063 TYPE : 0.8mm) The measurement shall be made with board in the bent position.  (Unit: mm)

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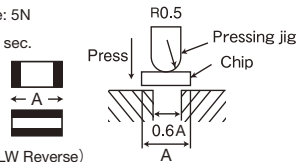
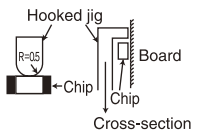
	Temperature Compensating (Class 1)		High Permittivity (Class 2)		
	Standard	High Frequency Type	Standard Note1	High Value	
10.Body Strength	—	No mechanical damage.	—	—	High Frequency Multilayer: Applied force: 5N Duration: 10 sec. 
11.Adhesion of Electrode	No separation or indication of separation of electrode.				Applied force: 5N Duration: 30±5 sec. (01005, 0201, 0302 TYPE 2N) 
12.Solderability	At least 95% of terminal electrode is covered by new solder.				Solder temperature: 230±5℃ Duration: 4±1 sec.
13.Resistance to soldering	Appearance: No abnormality Capacitance change: Within ±2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±2.5% Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±7.5% (BJ) Within ±20% (F) tan δ: Initial value Note 4 Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality		Preconditioning: Thermal treatment (at 150℃ for 1 hr) (Applicable to Class 2.) Solder temperature: 270±5℃ Duration: 3±0.5 sec. Preheating conditions: 80 to 100℃, 2 to 5 min. or 5 to 10 min. 150 to 200℃, 2 to 5 min. or 5 to 10 min. Recovery: Recovery for the following period under the standard condition after the test. 6~24 hrs (Class 1) 24±2 hrs (Class 2)
14.Thermal shock	Appearance: No abnormality Capacitance change: Within ±2.5% or ±0.25pF, whichever is larger. Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±0.25pF Q: Initial value Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality	Appearance: No abnormality Capacitance change: Within ±7.5% (BJ) Within ±20% (F) tan δ: Initial value Note 4 Insulation resistance: Initial value Withstanding voltage (between terminals): No abnormality		Preconditioning: Thermal treatment (at 150℃ for 1 hr) (Applicable to Class 2.) Conditions for 1 cycle: Step 1: Minimum operating temperature $^{+0}_{-3}$ ℃ 30±3 min. Step 2: Room temperature 2 to 3 min. Step 3: Maximum operating temperature $^{-0}_{+3}$ ℃ 30±3 min. Step 4: Room temperature 2 to 3 min. Number of cycles: 5 times Recovery after the test: 6~24 hrs (Class 1) 24±2 hrs (Class 2)
15.Damp Heat (steady state)	Appearance: No abnormality Capacitance change: Within ±5% or ±0.5pF, whichever is larger. Q: C≧30 pF : Q≧350 10≦C＜30 pF: Q≧275 + 2.5C C＜10 pF : Q≧200 + 10C C: Nominal capacitance Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: Within ±0.5pF, Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within ±12.5% F: Within ±30% tan δ: BJ: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: 50 MΩ μF or 1000 MΩ whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ:Within ±12.5% Note 4 tan δ: BJ: 5.0% max. Note 4. F: 11.0% max. Insulation resistance: 50 MΩ μF or 1000 MΩ whichever is smaller. Note 5	Multilayer： Preconditioning: Thermal treatment (at 150℃ for 1 hr) (Applicable to Class 2.) Temperature: 40±2℃ Humidity: 90 to 95% RH Duration: 500 $^{+24}_{-0}$hrs Recovery: Recovery for the following period under the standard condition after the removal from test chamber. 6~24 hrs (Class 1) 24±2 hrs (Class 2) High－Frequency Multilayer: Temperature: 60±2℃ Humidity: 90 to 95% RH Duration: 500 $^{+24}_{-0}$hrs Recovery: Recovery for the following period under the standard condition after the removal from test chamber. 6~24 hrs (Class 1)

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	Standard	High Frequency Type	Standard Note1	High Value	
16.Loading under Damp Heat	Appearance: No abnormality Capacitance change: Within ±7.5% or ±0.75pF, whichever is larger. Q: C≧30 pF: Q≧200 C<30 pF: Q≧100 + 10C/3 C : Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: C≦2 pF: Within ±0.4 pF C>2 pF: Within ±0.75 pF C : Nominal capacitance Insulation resistance: 500 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within ±12.5% F: Within ±30% Note 4 tan δ : BJ: 5.0% max. F: 7.5% max. Note 4 Insulation resistance: 25 MΩ μF or 500 MΩ, whichever is the smaller. Note 5	Appearance: No abnormality Capacitance change: BJ : Within±12.5% F : Within±30% Note 4 tan δ : BJ : 5.0%max. F : 11%max. Note 4 Insulation resistance: 25 MΩ μF or 500 MΩ, whichever is the smaller. Note 5	According to JIS C 5102 Clause 9. 9. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature: 40±2℃ Humidity: 90 to 95% RH Duration: 500 $^{+24}_{-0}$hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. (Class 1,2) Recovery: Recovery for the following period under the standard condition after the removal from test chamber. 6~24 hrs (Class 1) 24±2 hrs (Class 2) High−Frequency Multilayer: Temperature: 60±2℃ Humidity: 90 to 95% RH Duration: 500 $^{+24}_{-0}$hrs Applied voltage: Rated voltage Charge and discharge current: 50mA max. Recovery: 6~24 hrs of recovery under the standard condition after the removal from test chamber.
17.Loading at High Temperature	Appearance: No abnormality Capacitance change: Within ±3% or ±0.3pF, whichever is larger. Q: C≧30 pF : Q≧350 10≦C<30 pF: Q≧275 + 2.5C C<10 pF: Q≧200 + 10C C : Nominal capacitance Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: Within ±3% or ±0.3pF, whichever is larger. Insulation resistance: 1000 MΩ min.	Appearance: No abnormality Capacitance change: BJ: Within ±12.5% F: Within ±30% Note 4 tan δ : BJ: 4.0% max. F: 7.5% max. Note 4 Insulation resistance: 50 MΩ μF or 1000 MΩ, whichever is smaller. Note 5	Appearance: No abnormality Capacitance change: BJ : Within±12.5% Within±20% ※※ Within±25% ※※ F : Within±30% Note 4 tan δ : BJ : 5.0%max. F : 11%max. Note 4 Insulation resistance: 50 MΩ μF or 1000 MΩ, whichever is smaller. Note 5	According to JIS C 5102 clause 9.10. Multilayer: Preconditioning: Voltage treatment (Class 2) Temperature:125±3℃ (Class 1, Class 2: B, BJ (X7R)) 85±2℃ (Class 2: BJ,F) Duration: 1000$^{+48}_{-0}$hrs Applied voltage: Rated voltage×2 Note 6 Recovery: Recovery for the following period under the standard condition after the removal from test chamber. 6~24 hrs (Class 1) 24±2 hrs (Class 2) High−Frequency Multilayer: Temperature: 125±3℃ (Class 1) Duration: 1000$^{+48}_{-0}$hrs Applied voltage: Rated voltage×2 Recovery: 6~24 hrs of recovery under the standard condition after the removal from test chamber.

Note 1 :For 105 type, specified in "High value".
Note 2 :Thermal treatment (Multilayer): 1 hr of thermal treatment at 150 +0 /−10 ℃ followed by 24±2 hrs of recovery under the standard condition shall be performed before the measurement.
Note 3 :Voltage treatment (Multilayer): 1 hr of voltage treatment under the specified temperature and voltage for testing followed by 24±2 hrs of recovery under the standard condition shall be performed before the measurement.
Note 4, 5 :The figure indicates typical inspection. Please refer to individual specifications.
Note 6 :Some of the parts are applicable in rated voltage×1.5. Please refer to individual specifications.

Note on standard condition: "standard condition" referred to herein is defined as follows: 5 to 35℃ of temperature, 45 to 85% relative humidity, and 86 to 106kPa of air pressure.
When there are questions concerning measurement results: In order to provide correlation data, the test shall be conducted under condition of 20±2℃ of temperature, 60 to 70% relative humidity, and 86 to 106kPa of air pressure. Unless otherwise specified, all the tests are conducted under the "standard condition."